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Performance of open-gate AlGaN/GaN HFET in various kinds of liquids

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1. Introduction

GaN-based materials are very promising for various chemical and biological sensor applications, because of their superb chemical stability and capability of high-temperature operation owing to their widegap nature. The pH response of GaN surfaces using ion-sensitive field-effect transistor (ISFET) structures was recently reported by Steinhoff and co-workers [1]. However, no work on the pH response to AlGaN surfaces was done, and mechanism of pH response is not fully understood yet. In addition, the sensing properties of open-gate AlGaN/GaN heterostructure FET (HFET) to polar liquids have not systematically been investigated so far.

The purpose of this paper is to investigate pH- and liquid-phase sensing characteristics of open-gate AlGaN/GaN HFET structures.

2. Fabrication process and electrochemical cell

As shown in **Figure 1**, we used AlGaN/GaN heterostructures with an Al composition of 0.23 and AlGaN thickness of 22 nm, grown on sapphire by metal-organic vapor phase epitaxy (MOVPE). The electron mobility and

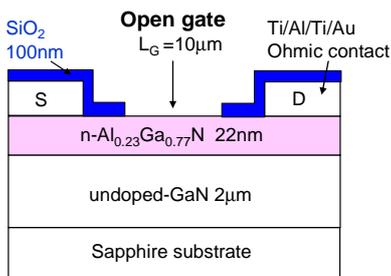


Fig1. The structure of the open-gate AlGaN/GaN HFET

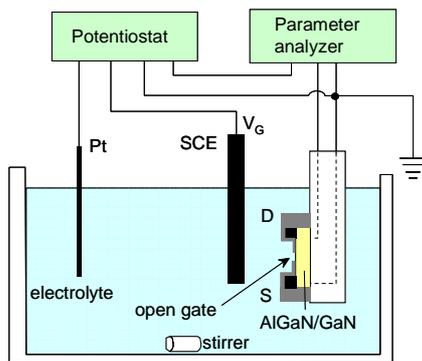


Fig2. Electrochemical cell

density of the two dimensional electron gas (2DEG) were $950 \text{ cm}^2/\text{V}$ and $8.0 \times 10^{12} \text{ cm}^{-2}$, respectively, at room temperature.

The device fabrication process started with isolation patterning using electron-cyclotron resonance-assisted reactive ion beam etching. The drain and source electrodes were formed by deposition of Ti/Al/Ti/Au multilayers. Then, the device surface was covered with SiO_2 film to a thickness of 100 nm using plasma-enhanced chemical vapor deposition. The open-gate area, length 10 μm and width 500 μm , was formed through photolithography and wet etching processes in a buffered HF solution. The final structure is shown in **Fig. 1**.

Figure 2 shows an electrochemical cell and a measurement circuit consisting of a potentiostat (EG&G, 273AEC) and a semiconductor parameter analyzer (Agilent, 4156C). The open-gate devices were set on a teflon holder, and the source and drain electrodes were covered by negative-type photoresist. The gate bias was applied from the semiconductor parameter analyzer to the electrolyte/AlGaN interface at the open-gate area via a saturated calomel electrode (SCE). For pH sensing measurements, we prepared deionized (DI) water and a mixed solution with HCl and NaOH in DI water. The pH values in solutions were measured using a digital pH meter (CyberScan, pH100). For polar liquids, we used ethanol and acetone. All measurements in solutions were performed at 24 °C under dark conditions.

3. Results and discussion

Figure 3 shows typical drain I-V characteristics of the open-gate HFET in DI water at 24 °C under dark conditions.

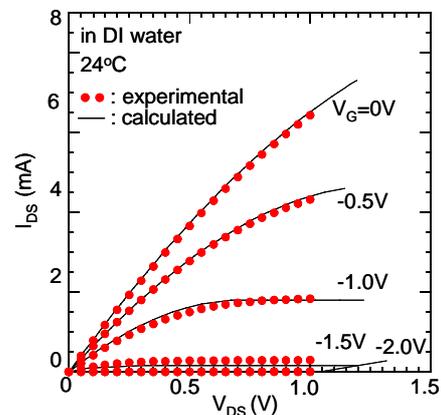
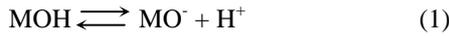


Fig3. Typical drain I-V characteristics of open-gate HFET in DI water

The device clearly exhibits current saturation and pinchoff behavior, which is very similar to I-V characteristics of typical Schottky-gate HFET. This shows that the potential of the AlGa_N surface in the open gate can effectively be controlled by the solution potential. The solid lines in Fig. 3 indicate the calculated curves based on the gradual-channel approximation together with a field-dependent mobility formula. The experimental I-V curves were reproduced very well by the calculation. From the calculated results, we estimated the value of 1.5 eV for the flat-band potential at the water/AlGa_N interface, which is very close to the charge neutrality level (CNL) of 1.6 eV for Al_{0.23}Ga_{0.77}N [3].

Figure 4 shows the transfer characteristics of the open-gate HFET in a mixed solution of HCl and NaOH in water with different pH values. To evaluate the transfer characteristics in the linear region, we set the drain bias at 0.2 V. A fine parallel shift was observed in the transfer curves, when the pH value changed from 4.0 to 10.0, indicating the corresponding potential change at the AlGa_N surface. The sensitivity for the potential change is 57.5 mV/pH, very close to the theoretical value of 58.9 mV/pH at 24 °C for the Nernstian response to H⁺ ions.

The exact mechanism of how these changes occur is still unknown. For electrolyte-insulator interfaces (SiO₂, SiN_x, Al₂O₃, AlN, etc.) in Si-based ion-sensitive FETs, however, a site-binding model is generally accepted [4, 5]. According to this model, hydroxyl groups (MOH: M represents Si or metals) are formed at insulator surfaces in contact with aqueous solutions, and can dissociate to or combine with H⁺, depending on the H⁺ concentration and the equilibrium constants for the relevant reactions, as follows:



When the H⁺ concentration decreases in solution, the right-direction reaction in the equilibrium equation (1) becomes dominant, resulting in negative charges at the insulator surfaces due to deprotonized hydroxyls (MO⁻). On

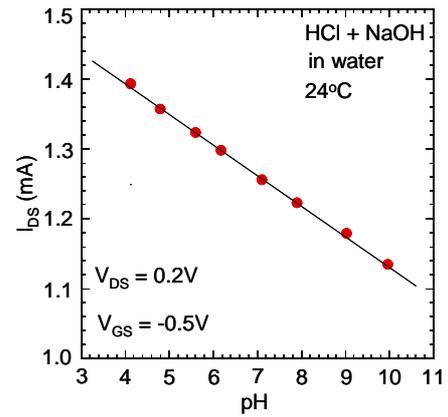
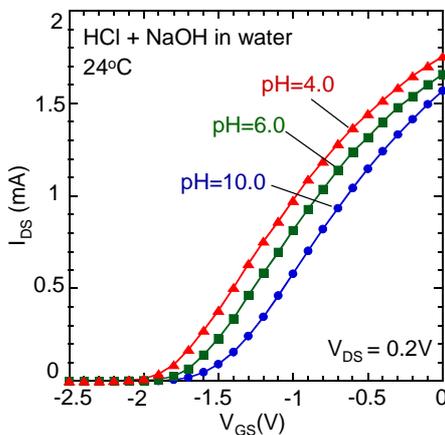


Fig5. Drain current as a function of pH value

the other hand, the increase of H⁺ can induce positive charges at the surfaces due to protonized hydroxyls (MOH₂⁺), represented by equation (2). This leads to a pH-dependent net charge at the insulator surfaces, and the liquid-solid interfacial potential thereby follows the Nernstian equation.

The simplest model for the present open-gate HFET is an analogy of this mechanism. On the other hand, there still remains the possibility that the potential at the solution-AlGa_N interface is governed by direct adsorption of ions at the given sites of the AlGa_N surface.

Figure 5 shows the drain current measured under V_{GS} = -0.5V and V_{DS} = 0.2V as a function of pH value. As expected from the result in Fig. 4, the drain current decreased with the pH value. A linear behavior was clearly observed, reflecting systematic change in potential at the AlGa_N surface in the linear bias region. In addition, we obtained a large current change, over 200 μA, when the pH value was changed from 4.3 to 10.0, because of high mobility and 2DEG density of the AlGa_N/Ga_N HFET.

The results obtained indicated that the open-gate AlGa_N/Ga_N HFET are very promising for high-sensitive liquid phase sensors.

References

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